



Sheet 1 of 1

Form PTO-1449 (REV. 1/06)		US Dept. of Commerce PATENT & TRADEMARK OFFICE	ATTY DOCKET NO. 128699	APPLICATION NO. 10/591,299
INFORMATION DISCLOSURE STATEMENT (Use several sheets if necessary)		APPLICANT(S) Susumu NODA et al.		
		FILING DATE August 31, 2006		
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U.S. PATENT DOCUMENTS				
Examiner Initials	Cite No.	Document Number	Date	Name
I		2003/0068152 A1	4/10/2003	GUNN, et al.
FOREIGN PATENT DOCUMENTS				
Examiner Initials	Cite No.	Document Number	Date	Country
2		EP 1 136 853 A1	9/26/2001	Europe
OTHER DOCUMENTS				
Examiner Initials	Cite No.	Including name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.		
3		WANG, RONGZHOU, et al., "Effects of Shapes and Orientations of Scatterers and Lattice Symmetries on the Photonic Band Gap on Two-Dimensional Photonic Crystals," Journal of Applied Physics , November 1, 2001, pages 4307-4313, vol. 90, no. 9; American Institute of Physics, New York, USA.		
4		GERARD, J.M., et al., "Photonic Bandgap of Two-Dimensional Dielectric Crystals," Solid-State Electronics, April 1, 1994, pages 1341-1344, vol. 37, nos. 4-6; Elsevier Science Ltd., Barking, Great Britain.		
5		FREZZA, FABRIZIO, et al., "Periodic Defects in 2D-PBG Materials: Full-Wave Analysis and Design," IEEE Transactions on Nanotechnology, September 1, 2003, pages 126-134, vol. 2, no. 3; IEEE Service Center, Piscataway, New Jersey, USA.		
EXAMINER <i>Kaveh Kianni/ (12/01/2009)</i>			DATE CONSIDERED	
Examiner: Initial if citation considered, whether or not citation is in conformance with M.P.E.P. 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.				